



SID4-SWIR

COST-EFFECTIVE SHORT WAVE IR WAVEFRONT SENSOR

The SID4-SWIR wavefront sensor integrates PHASICS patented technology with an InGaAs detector. Thanks to its high spatial resolution (80 x 64 phase pixels) and high sensitivity, it offers accurate wavefront measurement from 900 nm to 1.7 μ m. SID4-SWIR is an innovative solution for testing SWIR lens used in optical communications, inspection instruments or night vision in military and surveillance devices.

APPLICATIONS: Laser industry | FSOC | Automotive | Aerospace | Optical components

SPECIFICATIONS	
Wavelength range	0.9 - 1.7 μm
Aperture dimensions	9.60 x 7.68 mm ²
Phase spatial resolution	120 µm
Phase & Intensity sampling	80 x 64
Resolution (Phase)	< 2 nm RMS
Accuracy (Absolute)	15 nm RMS
Frame rate	100 fps
Real-time processing frequency	7 fps (full resolution)*
Interface	Giga Ethernet
Dimensions	100 x 55 x 63 mm ³
Weight	~ 500g
* with SID4 software	

